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[LMX2594](http://www.ti.com/product/lmx2594?qgpn=lmx2594) SNAS696C –MARCH 2017–REVISED APRIL 2019

LMX2594 15-GHz Wideband PLLATINUM™ RF Synthesizer With Phase Synchronization and JESD204B Support

1 Features

- 10-MHz to 15-GHz output frequency
- –110 dBc/Hz phase noise at 100-kHz offset with 15-GHz carrier
- 45-fs rms jitter at 7.5 GHz (100 Hz to 100 MHz)
- Programmable output power
- PLL key specifications
	- Figure of merit: –236 dBc/Hz
	- Normalized 1/f noise: –129 dBc/Hz
	- High phase detector frequency
		- 400-MHz integer mode
		- 300-MHz fractional mode
	- 32-bit fractional-N divider
- Remove integer boundary spurs with programmable input multiplier
- Synchronization of output phase across multiple devices
- Support for SYSREF with 9-ps resolution programmable delay
- Frequency ramp and chirp generation ability for FMCW applications
- < 20-µs VCO calibration speed
- 3.3-V single power supply operation

2 Applications

- 5G and mm-Wave wireless infrastructure
- Test and measurement equipment
- Radar
- MIMO
- Phased array antennas and beam forming
- • High-speed data converter clocking (supports JESD204B)

3 Description

The LMX2594 is a high-performance, wideband synthesizer that can generate any frequency from 10 MHz to 15 GHz without using an internal doubler, thus eliminating the need for sub-harmonic filters. The high-performance PLL with figure of merit of -236 dBc/Hz and high-phase detector frequency can attain very low in-band noise and integrated jitter. The highspeed N-divider has no pre-divider, thus significantly reducing the amplitude and number of spurs. There is also a programmable input multiplier to mitigate integer boundary spurs.

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 22

The LMX2594 allows users to synchronize the output of multiple devices and also enables applications that need deterministic delay between input and output. A frequency ramp generator can synthesize up to two segments of ramp in an automatic ramp generation option or a manual option for maximum flexibility. The fast calibration algorithm allows changing frequencies faster than 20 µs. The LMX2594 adds support for generating or repeating SYSREF (compliant to JESD204B standard) designed for low-noise clock sources in high-speed data converters. A fine delay adjustment (9-ps resolution) is provided in this configuration to account for delay differences of board traces.

The output drivers within LMX2594 deliver output power as high as 7 dBm at 15-GHz carrier frequency. The device runs from a single 3.3-V supply and has integrated LDOs that eliminate the need for on-board low noise LDOs.

Device Information[\(1\)](#page-0-0)

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Simplified Schematic

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Table of Contents

4 Revision History

Changes from Revision B (March 2018) to Revision C Page

Revision History (continued)

Changes from Revision A (August 2017) to Revision B Page

[LMX2594](http://www.ti.com/product/lmx2594?qgpn=lmx2594)

- Deleted redundant formula for Fout and also clarified SYSREF_DIV starts at 4 and counts by 2 [52](#page-51-1) • Deleted reference to VCO_CAPCTRL_EN, which is always 1, and clarified... [54](#page-53-0) • Changed text from: fMAX to: fHIGH... [55](#page-54-0) • Changed text from: RAMP_LIMIT_LOW=2³² - (f_{LOW} - f_{VCO}) / f_{PD} × 16777216 to: RAMP_LIMIT_LOW=2³³ - 16777216 x (fVCO - fLOW) / fPD .. [55](#page-54-1) **Changes from Original (March 2017) to Revision A Page** • Added DAP pin described as "Die Attach Pad".. [7](#page-6-1) • Added H2 Spec for 11 GHz ... [9](#page-8-2) • Clarified that output power assumes that load is matched and losses are de-embedded... [9](#page-8-3) • Changed "SDA" pin name mispelled. Should be "SDI". Also fixed in timing diagrams. Also added CE Pin [11](#page-10-5)
	- Removed the *OSCin Configuration* table and added content to the *OSCin Configuration* section...................................... [59](#page-58-2) • Changed pin 27 recommendation from 10 µF to 1 µF in [Figure](#page-60-1) 51... [61](#page-60-2)

• Swapped SDI and SCK in diagram ... [12](#page-11-1) • Added graphs and reordered ... [14](#page-13-0)

• Changed programming enumerations for RAMP_THRESH, RAMPx_LEN, and RAMP1_INC.. [34](#page-33-0) • Changed [Figure](#page-33-1) 29 .. [34](#page-33-2) • Changed SysRef description .. [35](#page-34-0) • Added divide by 2 to figure... [35](#page-34-1) • Changed some entries in the table .. [35](#page-34-2) • Changed fINTERPOLATOR SYSREF setup equation in [Table](#page-34-3) 18 .. [35](#page-34-4) • Changed SysRef delay from: 224 and 225 to: 225 and 226 .. [36](#page-35-0) • Changed "generator" mode to "master" mode. They mean the same thing .. [36](#page-35-1) • Changed description for SYSREF_DIV.. [36](#page-35-2) • Changed [Figure](#page-36-0) 31 .. [37](#page-36-1) • Changed wording for repeater mode and master mode... [38](#page-37-0) • Changed description of a few of the steps ... [39](#page-38-1) • Changed typo in R17 and R19 .. [48](#page-47-2) • Deleted reference to VCO_SEL_STRT_EN. This is always 1 ... [48](#page-47-3) • Added VCO_SEL_STRT_EN reference. This is always 1 ... [48](#page-47-4) • Changed the enumerations 0-3 and added content to the INPIN_LVL field description ... [50](#page-49-0) • Added Divide by 1' to SYSREF_DIV_PRE register description. Also fixed the name misspelling [52](#page-51-0)

Texas **STRUMENTS**

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5 Pin Configuration and Functions

6

Pin Functions

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *[Recommended](#page-7-3) Operating [Conditions](#page-7-3)*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

(1) JEDEC document JEP155 states that 500 V HBM allows safe manufacturing with a standard ESD control process. Manufacturing with less than 500 V HBM is possible with the necessary precautions. Pins listed as ±XXX V may actually have higher performance.

(2) JEDEC document JEP157 states that 250 V CDM allows safe manufacturing with a standard ESD control process. Manufacturing with less than 250 V CDM is possible with the necessary precautions. Pins listed as ±YYY V may actually have higher performance.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

6.4 Thermal Information

(1) For more information about traditional and new thermal metrics, see the *[Semiconductor](http://www.ti.com/lit/pdf/spra953) and IC Package Thermal Metrics* application report (SPRA953).

 (2) DAP

6.5 Electrical Characteristics

3.15 V \leq V_{CC} \leq 3.45 V, -40° C \leq T_A \leq +85°C. Typical values are at V_{CC} = 3.3 V, 25°C (unless otherwise noted).

(1) Single ended output power obtained after de-embedding microstrip trace losses and matching with a manual tuner. Unused port terminated to 50 ohm load.

(2) Output power, spurs, and harmonics can vary based on board layout and components.

(3) For lower VCO frequencies, the N divider minimum value can limit the phase-detector frequency.

 (4) The PLL noise contribution is measured using a clean reference and a wide loop bandwidth and is composed into flicker and flat components. PLL_flat = PLL_FOM + 20 × log(Fvco/Fpd) + 10 × log(Fpd / 1Hz). PLL_flicker (offset) = PLL_flicker_Norm + 20 × log(Fvco / 1GHz) – 10 × log(offset / 10kHz). Once these two components are found, the total PLL noise can be calculated as PLL_Noise = 10 ×
log(10 ^{PLL_Flat / 10 ₊ 10 ^{PLL_flicker / 10})}

Electrical Characteristics (continued)

3.15 V \leq V_{CC} \leq 3.45 V, -40° C \leq T_A \leq +85°C. Typical values are at V_{CC} = 3.3 V, 25°C (unless otherwise noted).

(5) See *Application and [Implementation](#page-58-0)* for more details on the different VCO calibration modes.

Electrical Characteristics (continued)

3.15 V \leq V_{CC} \leq 3.45 V, -40° C \leq T_A \leq +85°C. Typical values are at V_{CC} = 3.3 V, 25°C (unless otherwise noted).

6.6 Timing Requirements

 $(3.15 \text{ V} \le V_{CC} \le 3.45 \text{ V}, -40^{\circ}\text{C} \le T_A \le +85^{\circ}\text{C},$ except as specified. Nominal values are at $V_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$)

Timing Requirements (continued)

Figure 1. Serial Data Input Timing Diagram

There are several other considerations for writing on the SPI:

- The R/W bit must be set to 0.
- The data on SDI pin is clocked into a shift register on each rising edge on the SCK pin.
- The CSB must be held low for data to be clocked. Device will ignore clock pulses if CSB is held high.
- When SCK and SDI lines are shared between devices, TI recommends to hold the CSB line high on the device that is not to be clocked.
- Note that t_{CE} is only a valid spec if CPOL (Clock Polarity) = 0 and CPHA (Clock Phase) = 0 is used for SPI protocol. For SPI mode (CPOL = 1 and CPHA = 1), the minimum distance required between the last rising edge of clock and the rising edge of CSB is t_{CE} + clock_period/2.

Figure 2. Serial Data Readback Timing Diagram

There are several other considerations for SPI readback:

- The R/W bit must be set to 1.
- The MUXout pin will always be low for the address portion of the transaction.
- • The data on MUXout is clocked out at t_{CR} after the falling edge of SCK. In other words, the readback data will be available at the MUXout pin $\rm t_{CR}$ after the clock falling edge.
- The data portion of the transition on the SDI line is always ignored.

Texas **NSTRUMENTS**

6.7 Typical Characteristics

Typical Characteristics (continued)

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Typical Characteristics (continued)

Typical Characteristics (continued)

7 Detailed Description

7.1 Overview

The LMX2594 is a high-performance, wideband frequency synthesizer with integrated VCO and output divider. The VCO operates from 7.5 GHz to 15 GHz, and this can be combined with the output divider to produce any frequency in the range of 10 MHz to 15 GHz. Within the input path, there are two dividers and a multiplier for flexible frequency planning. The multiplier also allows the reduction of spurs by moving the frequencies away from the integer boundary.

The PLL is fractional-N PLL with a programmable delta-sigma modulator up to $4th$ order. The fractional denominator is a programmable 32-bit long, which can easily provide fine frequency steps below 1-Hz resolution, or be used to do exact fractions like 1/3, 7/1000, and many others. The phase frequency detector goes up to 300 MHz in fractional mode or 400 MHz in integer mode, although minimum N-divider values must also be taken into account.

For applications where deterministic or adjustable phase is desired, the SYNC pin can be used to get the phase relationship between the OSCin and RFout pins deterministic. When this is done, the phase can be adjusted in very fine steps of the VCO period divided by the fractional denominator.

The ultra-fast VCO calibration is designed for applications where the frequency must be swept or abruptly changed. The frequency can be manually programmed, or the device can be set up to do ramps and chirps.

The JESD204B support includes using the RFoutB output to create a differential SYSREF output that can be either a single pulse or a series of pulses that occur at a programmable distance away from the rising edges of the output signal.

The LMX2594 device requires only a single 3.3-V power supply. The internal power supplies are provided by integrated LDOs, eliminating the need for high-performance external LDOs.

The digital logic for the SPI interface and is compatible with voltage levels from 1.8 V to 3.3 V.

[Table](#page-17-2) 1 shows the range of several of the dividers, multipliers, and fractional settings.

Table 1. Range of Dividers, Multipliers, and Fractional Settings

7.2 Functional Block Diagram

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7.3 Feature Description

7.3.1 Reference Oscillator Input

The OSCin pins are used as a frequency reference input to the device. The input is high impedance and requires AC-coupling caps at the pin. A CMOS clock or XO can drive the single-ended OSCin pins. Differential clock input is also supported, making it easier to interface with high-performance system clock devices such as TI's LMK series clock devices. As the OSCin signal is used as a clock for the VCO calibration, a proper reference signal must be applied at the OSCin pin at the time of programming FCAL_EN.

7.3.2 Reference Path

The reference path consists of an OSCin doubler (OSC_2X), Pre-R divider, multiplier (MULT) and a Post-R divider.

Figure 22. Reference Path Diagram

The OSCin doubler (OSC_2X) can double up low OSCin frequencies. Pre-R (PLL_R_PRE) and Post-R (PLL_R) dividers both divide frequency down while the multiplier (MULT) multiplies frequency up. The purposes of adding a multiplier is to reduce integer boundary spurs or to increase the phase detector frequency. Use [Equation](#page-18-3) 1 to calculate the phase detector frequency, f_{PD} :

 $f_{PD} = f_{OSC} \times \text{OSC}_2$ X × MULT / (PLL_R_PRE × PLL_R) (1)

- • In the OSCin doubler or input multiplier is used, the OSCin signal should have a 50% duty cycle as both the rising and falling edges are used.
- If neither the OSCin doubler nor the input multiplier are used, only rising edges of the OSCin signal are used and duty cycle is not critical.
- The input multiplier and OSCin doubler should not both be used at the same time.

Feature Description (continued)

7.3.2.1 OSCin Doubler (OSC_2X)

The OSCin doubler allows one to double the input reference frequency up to 400 MHz. This doubler adds minimal noise and is useful for raising the phase detector frequency for better phase noise and also to avoid spurs. When the phase-detector frequency is increased, the flat portion of the PLL phase noise improves.

Figure 23. Benefit of Using the OSC_2X Doubler at 14 GHz

7.3.2.2 Pre-R Divider (PLL_R_PRE)

The Pre-R divider is useful for reducing the input frequency so that the programmable multiplier (MULT) can be used to help meet the maximum 250-MHz input frequency limitation to the PLL-R divider. Otherwise, it does not have to be used.

7.3.2.3 Programmable Multiplier (MULT)

The MULT is useful for shifting the phase-detector frequency to avoid integer boundary spurs. The multiplier allows a multiplication of 3, 4, 5, 6, or 7. Be aware that unlike the doubler, the programmable multiplier degrades the PLL figure of merit. This only would matter, however, for a clean reference and if the loop bandwidth was wide.

7.3.2.4 Post-R Divider (PLL_R)

The Post-R divider can be used to further divide down the frequency to the phase detector frequency. When it is used (PLL $R > 1$), the input frequency to this divider is limited to 250 MHz.

7.3.2.5 State Machine Clock

The state machine clock is a divided down version of the OSCin signal that is used internally in the device. This divide value is 1, 2, 4, or 8, and is determined by CAL_CLK_DIV programming word (described in the *[Programming](#page-39-0)* section). This state machine clock impacts various features like the lock detect delay, VCO calibration, and ramping. The state machine clock is calculated as $f_{\rm smclk}$ = $f_{\rm OSC}$ / 2^{CAL_CLK_DIV}.

7.3.3 PLL Phase Detector and Charge Pump

The phase detector compares the outputs of the Post-R divider and N-divider, and generates a correction current corresponding to the phase error until the two signals are aligned in-phase. This charge-pump current is software programmable to many different levels, allowing modification of the closed-loop bandwidth of the PLL. See the *Application [Information](#page-58-1)* section for more information.

Feature Description (continued)

7.3.4 N-Divider and Fractional Circuitry

The N-divider includes fractional compensation and can achieve any fractional denominator from 1 to $(2^{32} - 1)$. The integer portion of N is the whole part of the N-divider value, and the fractional portion, $N_{\text{frac}} = NUM / DEN$, is the remaining fraction. In general, the total N-divider value is determined by $N + NUM / DEN$. The N, NUM and DEN are software programmable. The higher the denominator, the finer the resolution step of the output. For example, even when using f_{PD} = 200 MHz, the output can increment in steps of 200 MHz / ($2^{32} - 1$) = 0.047 Hz. [Equation](#page-20-6) 2 shows the relationship between the phase detector and VCO frequencies. Note that in SYNC mode, there is an extra divider that is not shown in [Equation](#page-20-6) 2.

$$
f_{VCO} = f_{pd} \times \left(N + \frac{NUM}{DEN} \right) \tag{2}
$$

The sigma-delta modulator that controls this fractional division is also programmable from integer mode to fourth order. To make the fractional spurs consistent, the modulator is reset any time that the R0 register is programmed.

The N-divider has minimum value restrictions based on the modulator order and VCO frequency. Furthermore, the PFD_DLY_SEL bit must be programmed in accordance to the [Table](#page-20-7) 2.

Table 2. Minimum N-Divider Restrictions

7.3.5 MUXout Pin

The MUXout pin can be used to readback programmable states of the device or for lock detect.

7.3.5.1 Lock Detect

The MUXout pin can be configured for lock detect done in by reading back the rb_LD_VTUNE field or using the pin as shown in the [Table](#page-20-3) 4.

FIELD	PROGRAMMING	DESCRIPTION		
LD TYPE	$0 = VCO$ Calibration Status I = Indirect Vtune	Select Lock Detect Type.		
LD DLY	0 to 65535	Only valid for Vtune lock detect. This is a delay in state machine cycles.		
OUT MUTE	$0 = Disabled$ = Enabled	Turns off outputs when lock detect is low.		

Table 4. Configuring the MUXout Pin for Lock Detect

VCO calibration status lock detect works by indicating a low signal on the MUXout pin whenever the VCO is calibrating or the LD_DLY counter is running. The delay from the LD_DLY is added to the true VCO calibration time (t_{VCOCAL}), so it can be used to account for the analog lock time of the PLL.

Indirect Vtune lock detect is based on internally generated voltage that is related to (but not the same as) the Vtune voltage of the charge pump. It indicates a high signal on MUXout pin or reads back state 2 of rb_LD_VTUNE when the device is locked.

7.3.5.2 Readback

The MUXout pin can be configured to read back useful information from the device. Common uses for readback are:

- 1. Read back registers to ensure that they have been programmed to the correct value.
- 2. Read back the lock detect status to determine if the PLL is in lock.
- 3. Read back VCO calibration information so that it can be used to improve the lock time.
- 4. Read back information to help troubleshoot.

7.3.6 VCO (Voltage-Controlled Oscillator)

The LMX2594 includes a fully integrated VCO. The VCO takes the voltage from the loop filter and converts this into a frequency. The VCO frequency is related to the other frequencies is shown in [Equation](#page-21-2) 3:

 $f_{VCO} = f_{PD} \times N$ divider (3)

7.3.6.1 VCO Calibration

To reduce the VCO tuning gain and therefore improve the VCO phase-noise performance, the VCO frequency range is divided into several different frequency bands. The entire range, 7.5 to 15 GHz, covers an octave that allows the divider to take care of frequencies below the lower bound. This creates the need for frequency calibration to determine the correct frequency band given a desired output frequency. The frequency calibration routine is activated any time that the R0 register is programmed with the FCAL_EN = 1. It is important that a valid OSCin signal must present before VCO calibration begins.

The VCO also has an internal amplitude calibration algorithm to optimize the phase noise which is also activated any time the R0 register is programmed.

The optimum internal settings for this are temperature dependent. If the temperature is allowed to drift too much without being recalibrated, some minor phase noise degradation could result. The maximum allowable drift for continuous lock, ΔT_{CL} , is stated in the electrical specifications. For this device, a number of 125°C means the device never loses lock if the device is operated under the *[Recommended](#page-7-3) Operating Conditions*.

The LMX2594 allows the user to assist the VCO calibration. In general, there are three kinds of assistance, as shown in [Table](#page-22-3) 5:

To do the partial assist for the VCO calibration, follow this procedure:

1. Determine the VCO Core

Find a VCO Core that includes the desired VCO frequency. If at the boundary of two cores, choose one based on phase noise or performance.

- 2. Calculate the VCO CapCode as follows:
- $VCO_CAPCTRL_STRT =$ round $(C_{CoreMin} (C_{CoreMin} C_{CoreMax}) \times (f_{VCO} f_{CoreMin}) / (f_{CoreMax} f_{CoreMin}))$ 3. Get the VCO amplitude setting from [Table](#page-22-5) 6.

VCO_DACISET_STRT = round $(A_{CoreMin} + (A_{CoreMax} - A_{CoreMin}) \times (f_{VCO} - f_{CoreMin})/(f_{CoreMax} - f_{CoreMin}))$

Table 6. VCO Core Ranges

NOTE

In the range of 11900 MHz to 12100 MHz, VCO assistance cannot be used, and the settings must be: VCO_SEL = 4, VCO_DACISET_STRT = 300, and VCO_CAPCTRL_STRT = 1. Outside this range, in the partial assist for the VCO calibration, the VCO calibration runs. This means that if the settings are incorrect, the VCO still locks with the correct settings. The only consequence is that the calibration time might be a little longer. The closer the calibration settings are to the true final settings, the faster the VCO calibration will be.

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7.3.6.2 Determining the VCO Gain

The VCO gain varies between the seven cores and is the lowest at the lowest end of the band and highest at the highest end of each band. For a more accurate estimation, use [Table](#page-23-2) 7:

Table 7. VCO Gain

Based on [Table](#page-23-2) 7, [Equation](#page-23-3) 4 can estimate the VCO gain for an arbitrary VCO frequency of f_{VCO} :

 $Kvco = Kvco1 + (Kvco2 - Kvco1) \times (f_{VCO} - f1) / (f2 - f1)$ (4)

7.3.7 Channel Divider

To go below the VCO lower bound of 7.5 GHz, the channel divider can be used. The channel divider consists of four segments, and the total division value is equal to the multiplication of them. Therefore, not all values are valid.

Figure 24. Channel Divider

When the channel divider is used, there are limitations on the values. [Table](#page-24-2) 8 shows how these values are implemented and which segments are used.

Table 8. Channel Divider Segments

The channel divider is powered up whenever an output (OUTx_MUX) is selected to the channel divider or SysRef, regardless of whether it is powered down or not. When an output is not used, TI recommends selecting the VCO output to ensure that the channel divider is not unnecessarily powered up.

Table 9. Channel Divider

7.3.8 Output Buffer

The RF output buffer type is open collector and requires an external pullup to Vcc. This component may be a 50- Ω resistor to target 50-Ω output impedance match, or an inductor for higher output power at the expense of the output impedance being far from 50 Ω. If inductor is used, it is recommended to follow with resistive pad for better impedance matching. The current to the output buffer increases for states 0 to 31 and then again from states 48 to 63. States 32 to 47 are redundant and mimic states 16 to 31. If using a resistor, limit the OUTx_PWR setting to 50. Higher settings may actually reduce power due to the voltage drop across the resistor.

Table 10. OUTx_PWR Recommendations for Resistor Pullup

7.3.9 Power-Down Modes

The LMX2594 can be powered up and down using the CE pin or the POWERDOWN bit. When the device comes out of the powered down state, either by resuming the POWERDOWN bit to zero or by pulling back CE pin HIGH, register R0 must be programmed with FCAL_EN high again to re-calibrate the device.

7.3.10 Phase Synchronization

7.3.10.1 General Concept

The SYNC pin allows one to synchronize the LMX2594 such that the delay from the rising edge of the OSCin signal to the output signal is deterministic. Initially, the devices are locked to the input, but are not synchronized. The user sends a synchronization pulse that is reclocked to the next rising edge of the OSCin pulse. After a given time, t₁, the phase relationship from OSCin to f_{OUT} will be deterministic. This time is dominated by the sum of the VCO calibration time, the analog setting time of the PLL loop, and the MASH_RST_CNT if used in fractional mode.

Figure 25. Devices Are Now Synchronized to OSCin Signal

When the SYNC feature is enabled, part of the channel divide may be included in the feedback path. This will be referred to as *IncludedDivide*

Figure 26. Phase SYNC Diagram

7.3.10.2 Categories of Applications for SYNC

The requirements for SYNC depend on certain setup conditions. In cases that the SYNC is not timing critical, it can be done through software by toggling the VCO_PHASE_SYNC bit from 0 to 1. When it is timing critical, then it must be done through the pin and the setup and hold times for the OSCin pin are critical. [Figure](#page-27-0) 27 gives the different categories.

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Figure 27. Determining the SYNC Category

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7.3.10.3 Procedure for Using SYNC

This procedure must be used to put the device in SYNC mode.

- 1. Use the flowchart to determine the SYNC category.
- 2. Make determinations for OSCin and using SYNC based on the category.
	- 1. If Category 4, SYNC cannot be performed in this setup.
	- 2. If category 3, ensure that the maximum f_{OSC} frequency for SYNC is not violated and there are hardware accommodations to use the SYNC pin.
- 3. Determine the value of IncludedDivide:
	- 1. If OUTA_MUX is not channel divider and OUTB_MUX is not channel divider or SysRef, then IncludedDivide = 1.
	- 2. Otherwise, IncludedDivide = $2 \times$ SEG1. In the case that the channel divider is 2, then IncludedDivide=4.
- 4. If not done already, divide the N-divider and fractional values by IncludedDivide to account for the IncludedDivide.
- 5. Program the device with the VCO_PHASE_SYNC = 1. Note that this does not count as applying a SYNC to device (for category 2).
- 6. Apply the SYNC, if required:
	- 1. If category 2, VCO_PHASE_SYNC can be toggled from 0 to 1. Alternatively, a rising edge can be sent to the SYNC pin and the timing of this is not critical.
	- 2. If category 3, the SYNC pin must be used, and the timing must be away from the rising edge of the OSCin signal. Toggling the SYNC pin runs VCO calibration when FCAL EN = 1. If FCAL EN = 0 then SYNC pin does not function.

7.3.10.4 SYNC Input Pin

The SYNC input pin can be driven either in CMOS or LVDS mode. However, if not using SYNC mode (VCO_PHASE_SYNC = 0), then the INPIN_IGNORE bit must be set to one, otherwise it causes issues with lock detect. If the pin is desired for to be used and VCO_PHASE_SYNC = 1, then set INPIN_IGNORE = 0. LVDS or CMOS mode may be used. LVDS works to 250 mVPP, but is not ensured in production.

7.3.11 Phase Adjust

The MASH SEED word can use the sigma-delta modulator to shift output signal phase with respect to the input reference. If a SYNC pulse is sent (software or pin) or the MASH is reset with MASH_RST_N, then this phase shift is from the initial phase of zero. If the MASH_SEED word is written to, then this phase is added. Use [Equation](#page-28-5) 5 to calculate the phase shift.

Phase shift in degrees = $360 \times (MASH)$ SEED / PLL DEN) \times (IncludedDivide / CHDIV) (5)

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Example:

Mash seed $= 1$

Denominator $= 12$

Channel divider = 16

Phase shift (VCO_PHASE_SYNC = 0) = 360 \times (1/12) \times (1/16) = 1.875 degrees

Phase Shift (VCO_PHASE_SYNC = 1) = 360 \times (1/12) \times (4/16) = 7.5 degrees

There are several considerations with phase shift with MASH_SEED:

- Phase shift can be done with a FRAC_NUM = 0, but MASH_ORDER must be greater than zero. For $MASH \n_QRDER = 1$, the phase shifting only occurs when $MASH \n_SEED$ is a multiple of PLL DEN.
- For the phase adjust, the condition PLL_DEN > PLL_NUM + MASH_SEED must be satisfied.
- • When MASH_SEED and Phase SYNC are used together with IncludedDivide > 1, additional constraints may be necessary to produce a monotonic relationship between MASH_SEED and the phase shift, especially when the VCO frequency is below 10 GHz. These constraints are application specific, but some general guidelines are to reduce modulator order and increase the N divider. One possible guideline is for PLL_N ≥ 45 (2nd order modulator), PLL_N ≥ 49 (3rd Order modulator), PLL_N ≥ 54 (4th Order Modulator).

7.3.12 Fine Adjustments for Phase Adjust and Phase SYNC

Phase SYNC refers to the process of getting the same phase relationship for every power-up cycle and each time assuming that a given programming procedure is followed. However, there are some adjustments that can be made to get the most accurate results. As for the consistency of the phase SYNC, the only source of variation could be if the VCO calibration chooses a different VCO core and capacitor, which can introduce a bimodal distribution with about 10 ps of variation. If this 10 ps is not desirable, then it can be eliminated by reading back the VCO core, capcode, and DACISET values and forcing these values to ensure the same calibration settings every time. The delay through the device varies from part to part and can be on the order of 60 ps. This part to part variation can be calibrated out with the MASH_SEED. The variation in delay through the device also changes on the order of +2.5 ps/°C, but devices on the same board likely have similar temperatures, so this will somewhat track. In summary, the device can be made to have consistent delay through the part and there are means to adjust out any remaining errors with the MASH_SEED. This tends only to be an issue at higher output frequencies when the period is shorter.

7.3.13 Ramping Function

The LMX2594 supports the ability to make ramping waveforms using manual mode or automatic mode. In manual mode, the user defines a step and uses the RampClk and RampDir pins to create the ramp. In automatic mode, the user sets up the ramp with up to two linear segments in advance and the device automatically creates this ramp. [Table](#page-29-5) 12 fields apply in both automatic mode and manual pin mode.

Table 12. Ramping Field Descriptions

Table 13. General Restrictions for Ramping

7.3.13.1 Manual Pin Ramping

Manual pin ramping is enabled by setting RAMP_EN = 1 and RAMP_MANUAL = 1. The rising edges are applied to the RampClk pin are reclocked to the phase detector frequency. The RampDir pin controls the size of the change. If a rising edge is seen on the RampClk pin while the VCO is calibrating, then this rising edge is ignored. The frequency for the RampClk must be limited to a frequency of 250 kHz or less, and the rising edge of the RampDir signal must be targeted away from the rising edges of the RampCLK pin.

Table 14. RAMP_INC

7.3.13.1.1 Manual Pin Ramping Example

In this ramping example, assume that we want to use the pins for UP/Down control of the ramp for 10-MHz steps and the phase detector is 100 MHz.

RAMP1_INC $\begin{bmatrix} 1072064102 \end{bmatrix}$ (–10 MHz)/ (100 MHz) × 16777216 = –1677722

RAMP_TRIG_CAL | 1 Recalibrate at every clock cycle

Table 15. Step Ramping Example

2's complement = 2^{30} – 1677722 = 1072064102

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7.3.13.2 Automatic Ramping

Automatic ramping is enabled when RAMP_EN = 1 and RAMP_MANUAL = 0. The action of programming FCAL = 1 starts the ramping. In this mode, there are two ramps that one can use to set the length and frequency change. In addition to this, there are ramp limits that can be used to create more complicated waveforms.

Automatic ramping can really be divided into two classes depending on if the VCO must calibrate in the middle of the ramping waveform or not. If the VCO can go the entire range without calibrating, this is calibration-free ramping, which is shown in *Typical [Characteristics](#page-13-0)*. Note that this range is less at hot temperatures and for lower frequency VCOs. This range is not ensured, so margin must be built into the design.

For waveforms that are NOT calibration free, the slew rate of the ramp must be kept less than 250 kHz/µs. Also, for all automatic ramping waveforms, be aware that there is a very small phase disturbance as the VCO crosses over the integer boundary, so one might consider using the input multiplier to avoid these or timing the VCO calibrations at integer boundaries.

FIELD	PROGRAMMING	DESCRIPTION
RAMP DLY	$0 =$ One clock cycle $1 = Two clock cycles$	Normally, the ramp clock is equal to the phase detector frequency. When this feature is enabled, it reduces the ramp clock by a factor of 2.
RAMPO LEN RAMP1 LEN	0 to 65535	This is the length of the ramp in clock cycles. Note that the VCO calibration time is added to this time.
RAMPO INC RAMP1 INC	0 to $2^{30} - 1$	2's complement of the value for the ramp increment.
RAMPO NEXT RAMP1 NEXT	$0 = RAMPO$ $1 = RAMP1$	Defines which ramp comes after the current ramp.
RAMPO NEXT TRIG RAMP1 NEXT TRIG	$0 =$ Timeout counter $1 = Trigger A$ $2 = Trigger B$ $3 =$ Reserved	Determines what triggers the action of the next ramp occurrence.
RAMP TRIG A RAMP_TRIG_B	$0 = Disabled$ $1 =$ RampClk rising edge $2 =$ RampDir rising edge $4 =$ Always triggered $9 =$ RampClk falling edge $10 =$ RampDir falling edge All other States = invalid	This field defines the ramp trigger.
RAMPO RST RAMP1 RST	$0 = Disable$ $1 =$ Enabled	Enabling this bit causes the ramp to reset to the original value when the ramping started. This is useful for roundoff errors.
RAMP BURST COUNT	0 to 8191	This is the number the ramping pattern repeats and only applies for a terminating ramping pattern.
RAMP BURST TRIG	$0 =$ Ramp Transition $1 = Trigger A$ $2 = Trigger B$ $3 =$ Reserved	This defines what causes the RAMP COUNT to increment.

Table 16. Automatic Ramping Field Descriptions

7.3.13.2.1 Automatic Ramping Example (Triangle Wave)

Suppose user wants to generate a sawtooth ramp that goes from 8 to 10 GHz in 2 ms (including calibration breaks) with a phase-detector frequency of 50 MHz. Divide this into segments of 50 MHz where the VCO ramps for 25 µs, then calibrates for 25 µs, for a total of 50 µs. There would therefore be 40 such segments which span over a 2-GHz range and would take 2 ms, including calibration time.

Table 17. Sawtooth Ramping Example

NOTE

To calculate ramp_scale_count and ramp_dly_cnt, remember that the desired calibration time is 25 µs.

Figure 29. Triangle Waveform Example

7.3.14 SYSREF

The LMX2594 can generate a SYSREF output signal that is synchronized to f_{OUT} with a programmable delay. This output can be a single pulse, series of pulses, or a continuous stream of pulses. To use the SYSREF capability, the PLL must first be placed in SYNC mode with VCO PHASE SYNC = 1.

Figure 30. SYSREF Setup

As [Figure](#page-34-5) 30 shows, the SYSREF feature uses IncludedDivide and SYSREF_DIV_PRE divider to generate f_{INTERPOLATOR}. This frequency is used for reclocking of the rising and falling edges at the SysRefReq pin. In master mode, the $f_{\text{INTERPOLATOR}}$ is further divided by 2 x SYSREF_DIV to generate finite series or continuous stream of pulses.

The delay can be programmed using the JESD_DAC1_CTRL, JESD_DAC2_CTRL, JESD_DAC3_CTRL, and JESD_DAC4_CTRL words. By concatenating these words into a larger word called "SYSREFPHASESHIFT", the relative delay can be found. The sum of these words should always be 63.

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Table 19. SysRef Delay

7.3.14.1 Programmable Fields

[Table](#page-35-4) 20 has the programmable fields for the SYSREF functionality.

7.3.14.2 Input and Output Pin Formats

7.3.14.2.1 Input Format for SYNC and SysRefReq Pins

These pins are single-ended, but a differential signal can be converted to drive them. In the LVDS mode, if the INPIN_FMT is set to LVDS mode, then the bias level can be adjusted with INPIN_LVL and the hysteresis can be adjusted with INPIN_HYST.

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Figure 31. Driving SYNC/SYSREF With Differential Signal

7.3.14.2.2 SYSREF Output Format

The SYSREF output comes in differential format through RFoutB. This will have a minimum voltage of about 2.3 V and a maximum of 3.3 V. If DC coupling cannot be used, there are two strategies for AC coupling.

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Figure 32. SYSREF Output

- 1. Send a series of pulses to establish a DC-bias level across the AC-coupling capacitor.
- 2. Establish a bias voltage at the data converter that is below the threshold voltage by using a resistive divider.

7.3.14.3 Examples

The SysRef can be used in a repeater mode (SYSREF_REPEAT = 1), which just echos the SysRefReq pin, after being reclocked to the $f_{\text{INTERPOLATOR}}$ frequency and then f_{OUT} (from RFoutA).

Figure 33. SYSREF Out In Repeater Mode

In master mode (SYSREF_REPEAT = 0), rising and falling edges at the SysRefReq pin are first reclocked to the $f_{\rm OSC}$, then $f_{\text{INTERPOLATOR}}$, and finally to f_{OUT} . A programmable number of pulses is generated with a frequency equal to f_{VCO} / (2 × IncludedDivide × SYSREF_DIV_PRE × SYSREF_DIV). In continuous mode (SYSREF_PULSE = 0), the SysRefReq pin is held high to generate a continuous stream of pulses. In pulse mode (SYSREF_PULSE = 1), a finite number of pulses determined by SYSREF_PULSE_CNT is sent for each rising edge of the SysRefReq pin.

Figure 34. Figure 1. SYSREF Out In Pulsed/Continuous Mode

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7.3.14.4 SYSREF Procedure

- 1. Put the device in SYNC mode using the procedure already outlined.
- 2. Figure out IncludedDivide the same way it is done for SYNC mode.
- 3. Calculate the SYSREF_DIV_PRE value such that the interpolator frequency (f_{INTERPOLATOR}) is in the range of 800 to 1500 MHz. $f_{\text{INTERPOLATOR}} = f_{\text{VCO}}/$ IncludedDivide/SYSREF_DIV_PRE. Make this frequency a multiple of f_{OSC} if possible.
- 4. If using continuous mode (SYSREF_PULSE = 0), ensure the SysRefReq pin is high.
- 5. If using pulse mode (SYSREF_PULSE = 1), set up the pulse count as desired. Pulses are created by toggling the SysRefReq pin.
- 6. Adjust the delay between the RFoutA and RFoutB signal using the JESD_DACx_CTL fields.

7.3.15 SysRefReq Pin

The SysRefReq pin can be used in CMOS all the time, or LVDS mode is also optional if SYSREF_REPEAT = 1. LVDS mode cannot be used in master mode.

7.4 Device Functional Modes

Although there are a vast number of ways to configure this device, only one is really functional.

Table 21. Device Functional Modes

[LMX2594](http://www.ti.com/product/lmx2594?qgpn=lmx2594)

7.5 Programming

The LMX2594 is programmed using 24-bit shift registers. The shift register consists of a R/W bit (MSB), followed by a 7-bit address field and a 16-bit data field. For the R/W bit, 0 is for write, and 1 is for read. The address field ADDRESS[6:0] is used to decode the internal register address. The remaining 16 bits form the data field DATA[15:0]. While CSB is low, serial data is clocked into the shift register upon the rising edge of clock (data is programmed MSB first). When CSB goes high, data is transferred from the data field into the selected register bank. See [Figure](#page-11-0) 1 for timing details.

7.5.1 Recommended Initial Power-Up Sequence

For the most reliable programming, TI recommends this procedure::

- 1. Apply power to device.
- 2. Program RESET = 1 to reset registers.
- 3. Program $RESET = 0$ to remove reset.
- 4. Program registers as shown in the register map in REVERSE order from highest to lowest.
- 5. Wait 10 ms.
- 6. Program register R0 one additional time with FCAL_EN = 1 to ensure that the VCO calibration runs from a stable state.

7.5.2 Recommended Sequence for Changing Frequencies

The recommended sequence for changing frequencies is as follows:

- 1. Change the N-divider value.
- 2. Program the PLL numerator and denominator.
- 3. Program FCAL_EN (R0[3]) = 1.

7.5.3 General Programming Requirements

Follow these requirements when programming the device:

- 1. For register bits that do not have field names in [Table](#page-40-0) 23, it is necessary to program these values just as shown in the register map.
- 2. Not all registers need to be programmed. Refer to [Table](#page-39-0) 22 for details.
- 3. Power-on-reset register values may not be optimal, so it is always necessary to program all of the required registers after powering on the device. Note that the 'Reset' column in register descriptions is the power-onreset value.

Table 22. Programming Requirement

7.6 Register Maps

Table 23. Full Register Map

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Table 23. Full Register Map (continued)

Table 23. Full Register Map (continued)

Table 23. Full Register Map (continued)

ISTRUMENTS

EXAS

7.6.1 General Registers R0, R1, & R7

Figure 35. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

Table 24. Field Descriptions

7.6.2 Input Path Registers

Figure 36. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

Table 25. Field Descriptions

7.6.3 Charge Pump Registers (R13, R14)

Figure 37. Registers Excluding Address

LEGEND: $R/W = Read/Write$; $R = Read$ only; -n = value after reset

Table 26. Field Descriptions

STRUMENTS

EXAS

7.6.4 VCO Calibration Registers

Figure 38. Registers Excluding Address

LEGEND: $R/W = Read/Write$; $R = Read$ only; -n = value after reset

Table 27. Field Descriptions

7.6.5 N Divider, MASH, and Output Registers

Figure 39. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

Table 28. Field Descriptions

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STRUMENTS

EXAS

Table 28. Field Descriptions (continued)

7.6.6 SYNC and SysRefReq Input Pin Register

Figure 40. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

Table 29. Field Descriptions

7.6.7 Lock Detect Registers

Figure 41. Registers Excluding Address

LEGEND: $R/W = Read/Write$; $R = Read$ only; -n = value after reset

Table 30. Field Descriptions

7.6.8 MASH_RESET

Figure 42. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

Table 31. Field Descriptions

7.6.9 SysREF Registers

Figure 43. Registers Excluding Address

LEGEND: $R/W = Read/Write$; $R = Read$ only; -n = value after reset

Table 32. Field Descriptions

7.6.10 CHANNEL Divider Registers

Figure 44. Registers Excluding Address

Table 33. Field Descriptions

ISTRUMENTS

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7.6.11 Ramping and Calibration Fields

Figure 45. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

Table 34. Field Descriptions

7.6.12 Ramping Registers

These registers are only relevant for ramping functions and are enabled if and only if RAMP_EN (R0[15]) = 1.

7.6.12.1 Ramp Limits

Figure 46. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

Table 35. Field Descriptions

7.6.12.2 Ramping Triggers, Burst Mode, and RAMP0_RST

Figure 47. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

STRUMENTS

EXAS

7.6.12.3 Ramping Configuration

Figure 48. Registers Excluding Address

LEGEND: $R/W = Read/Write$; $R = Read$ only; -n = value after reset

Table 37. Field Descriptions

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ISTRUMENTS

FXAS

Table 37. Field Descriptions (continued)

7.6.13 Readback Registers

Figure 49. Registers Excluding Address

LEGEND: R/W = Read/Write; R = Read only; -n = value after reset

Table 38. Field Descriptions

8 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

8.1.1 OSCin Configuration

The OSCin supports single-ended or differential clocks. There must be a AC-coupling capacitor in series before the device pin. The OSCin inputs are high-impedance CMOS with internal bias voltage. TI recommends putting termination shunt resistors to terminate the differential traces (if there are 50-Ω characteristic traces, place 50- Ω resistors). The OSCin and OSCin* side should be matched in layout. A series AC-coupling capacitors should immediately follow OSCin pins in the board layout, then the shunt termination resistors to ground should be placed after.

Input clock definitions are shown in [Figure](#page-58-0) 50:

Figure 50. Input Clock Definitions

8.1.2 OSCin Slew Rate

The slew rate of the OSCin signal can impact the spurs and phase noise of the LMX2594 if it is too low. In general, a high slew rate and a lower amplitude signal, such as LVDS, can give best performance.

8.1.3 RF Output Buffer Power Control

The OUTA, PWR and OUTB, PWR registers can be used to control the output power of the output buffers. The setting for optimal power may depend on the pullup component, but is typically around 50. The higher the setting, the higher the current consumption of the output buffer.

8.1.4 RF Output Buffer Pullup

The choice of output buffer components is very important and can have a profound impact on the output power. [Table](#page-59-0) 39 shows how to treat each pin. If using a single-ended output, a pullup is required, and the user can put a 50- $Ω$ resistor after the capacitor.

Application Information (continued)

Table 39. Different Methods for Pullup on Outputs

Table 40. Output Pullup Configuration

8.2 Typical Application

8.2.1 Design Requirements

The design of the loop filter is complex and is typically done with software. The PLLATINUM™ Sim software is an excellent resource for doing this and the design is shown in the [Figure](#page-61-0) 52. For those interested in the equations involved, the *PLL [Performance,](http://www.ti.com/lit/pdf/SNAA106) Simulation, and Design Handbook* listed in the end of this document goes into great detail as to the theory and design of PLL loop filters.

Figure 52. PLLATINUM™ Sim Design Screen

8.2.2 Detailed Design Procedure

The integration of phase noise over a certain bandwidth (jitter) is an performance specification that translates to signal-to-noise ratio. Phase noise inside the loop bandwidth is dominated by the PLL, while the phase noise outside the loop bandwidth is dominated by the VCO. Generally, jitter is lowest if the loop bandwidth is designed to the point where the two intersect. A higher phase margin loop filter design has less peaking at the loop bandwidth and thus lower jitter. The tradeoff with this is that longer lock times and spurs must be considered in design as well.

8.2.3 Application Curve

9 Power Supply Recommendations

If fractional spurs are a large concern, using a ferrite bead to each of these power supply pins can reduce spurs to a small degree. This device has integrated LDOs, which improves the resistance to power supply noise. However, the pullup components on the RFoutA and RFoutB pins on the outputs have a direct connection to the power supply, take extra care to ensure that the voltage is clean for these pins. *[Figure](#page-63-0) 54* is a typical application example.

This device can be powered by an external DC-DC buck converter, such as the TPS62150. Note that although Rtps, Rtps1, and Rtps2 are 0 Ω in the schematic, they could be potentially replaced with a larger resistor value or inductor value for better power supply filtering.

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Figure 54. Using the TPS62150 as a Power Supply

For DC bias levels, refer to .

Table 41. Bias Levels of Pins

(1) The bias level is measured after following [Recommended](#page-39-1) Initial Power-Up Sequence.

10 Layout

10.1 Layout Guidelines

In general, the layout guidelines are similar to most other PLL devices. Here are some specific guidelines.

- GND pins may be routed on the package back to the DAP.
- The OSCin pins are internally biased and must be AC-coupled.
- If not used, RampClk, RampDir, and SysRefReq can be grounded to the DAP.
- For the Vtune pin, try to place a loop filter capacitor as close as possible to the pin. This may mean separating the capacitor from the rest of the loop filter.
- For the outputs, keep the pullup component as close as possible to the pin and use the same component on each side of the differential pair.
- If a single-ended output is needed, the other side must have the same loading and pullup. However, the routing for the used side can be optimized by routing the complementary side through a via to the other side of the board. On this side, use the same pullup and make the load look equivalent to the side that is used.
- Ensure that DAP on device is well-grounded with many vias, preferably copper filled.
- Have a thermal pad that is as large as the LMX2594 exposed pad. Add vias to the thermal pad to maximize thermal performance.
- Use a low loss dielectric material, such as Rogers 4003, for optimal output power.
- See instructions for the LMX2594EVM (*LMX2594 EVM [Instructions,](http://www.ti.com/lit/pdf/SNAU210) 15 GHz Wideband Low Noise PLL With [Integrated](http://www.ti.com/lit/pdf/SNAU210) VCO*) for more details on layout.

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10.2 Layout Example

Figure 55. LMX2594 PCB Layout

11 Device and Documentation Support

11.1 Device Support

11.1.1 Third-Party Products Disclaimer

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11.1.2 Development Support

Texas Instruments has several software tools to aid in the development at [www.ti.com.](http://www.ti.com) Among these tools are:

- EVM software to understand how to program the device and for programming the EVM board.
- EVM board instructions for seeing typical measured data with detailed measurement conditions and a complete design.
- PLLatinum Sim program for designing loop filters, simulating phase noise, and simulating spurs .

11.2 Documentation Support

11.2.1 Related Documentation

For related documentation see the following:

- *AN-1879 Fractional N [Frequency](http://www.ti.com/lit/pdf/SNAA062) Synthesis* (SNAA062)
- *PLL [Performance,](http://www.ti.com/lit/pdf/SNAA106) Simulation, and Design Handbook* (SNAA106)
- *LMX2594 EVM [Instructions](http://www.ti.com/lit/pdf/SNAU210) –15-GHz Wideband Low Noise PLL With Integrated VCO* (SNAU210)

11.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.4 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms](http://www.ti.com/corp/docs/legal/termsofuse.shtml) of [Use.](http://www.ti.com/corp/docs/legal/termsofuse.shtml)

TI E2E™ Online [Community](http://e2e.ti.com) *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design [Support](http://support.ti.com/) *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

11.5 Trademarks

PLLATINUM, E2E are trademarks of Texas Instruments. All other trademarks are the property of their respective owners.

11.6 Electrostatic Discharge Caution

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

11.7 Glossary

[SLYZ022](http://www.ti.com/lit/pdf/SLYZ022) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices mav have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

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PACKAGE MATERIALS INFORMATION

*All dimensions are nominal

MECHANICAL DATA

All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994. Α.

- **B.** This drawing is subject to change without notice.
- QFN (Quad Flatpack No-Lead) Package configuration. С.
- The package thermal pad must be soldered to the board for thermal and mechanical performance. D.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- F. Package complies to JEDEC MO-220 variation VJJD-2.

RHA (S-PVQFN-N40)

PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

PLASTIC QUAD FLATPACK NO-LEAD

NOTES:

- All linear dimensions are in millimeters. А.
- This drawing is subject to change without notice. **B.**
- Publication IPC-7351 is recommended for alternate designs. C.
- This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack D. Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil desian recommendations. Refer to IPC 7525 for stencil desian considerations.
- F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.

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